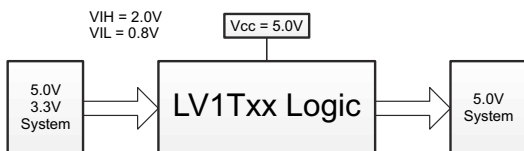


SN74LV1T02 单电源 2 输入正或非门 CMOS 逻辑电平转换器

1 特性

- V_{CC} 为 5.0V、3.3V、2.5V 和 1.8V 的单电源电压转换器
- 工作电压范围为 1.8V 至 5.5V
- 升压转换：
 - 1.8V V_{CC} 时为 1.2V⁽¹⁾ 至 1.8V
 - 2.5V V_{CC} 时为 1.5V⁽¹⁾ 至 2.5V
 - 3.3V V_{CC} 时为 1.8V⁽¹⁾ 至 3.3V
 - 5.0V V_{CC} 时为 3.3V 至 5.0V
- 降压转换：
 - 1.8V V_{CC} 时为 3.3V 至 1.8V
 - 2.5V V_{CC} 时为 3.3V 至 2.5V
 - 3.3V V_{CC} 时 5.0V 至 3.3V
- 逻辑输出以 V_{CC} 为基准
- 输出驱动：
 - 电压为 5V 时，输出驱动为 8mA
 - 电压为 3.3V 时，输出驱动为 7mA
 - 电压为 1.8V 时，输出驱动为 3mA
- 3.3V V_{CC} 时，频率高达 50MHz
- 输入引脚可耐受 5V 电压
- -40°C 至 125°C 工作温度范围
- 可提供无铅封装：SC-70 (DCK)



- 2mm x 2.1mm x 0.65mm (高度 1.1mm)

- 闩锁性能超过 250mA，符合 JESD 17 规范
- 支持标准逻辑引脚排列
- 与 AUP1G 和 LVC1G 系列兼容的 CMOS 输出 B¹

2 应用

- 电信
- 便携式应用
- 服务器
- PC 和笔记本电脑

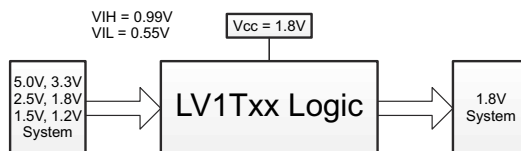
3 说明

SN74LV1T02 是一款具有较低输入阈值的单通道 2 输入或非门，可支持电压转换应用。

封装信息

器件型号	封装 ⁽¹⁾	封装尺寸 ⁽²⁾	本体尺寸 ⁽³⁾
SN74LV1T02	DBV (SOT-23, 5)	2.90mm x 2.8mm	2.9mm x 1.6mm
	DCK (SC-70, 5)	2.00mm x 2.1mm	2mm x 1.25mm

- (1) 如需了解所有可用封装，请参阅数据表末尾的可订购产品附录。
- (2) 封装尺寸 (长 x 宽) 为标称值，并包括引脚 (如适用)。
- (3) 本体尺寸 (长 x 宽) 为标称值，不包括引脚。



¹ 请参考较低 V_{CC} 条件下的 V_{IH}/V_{IL} 和输出驱动。



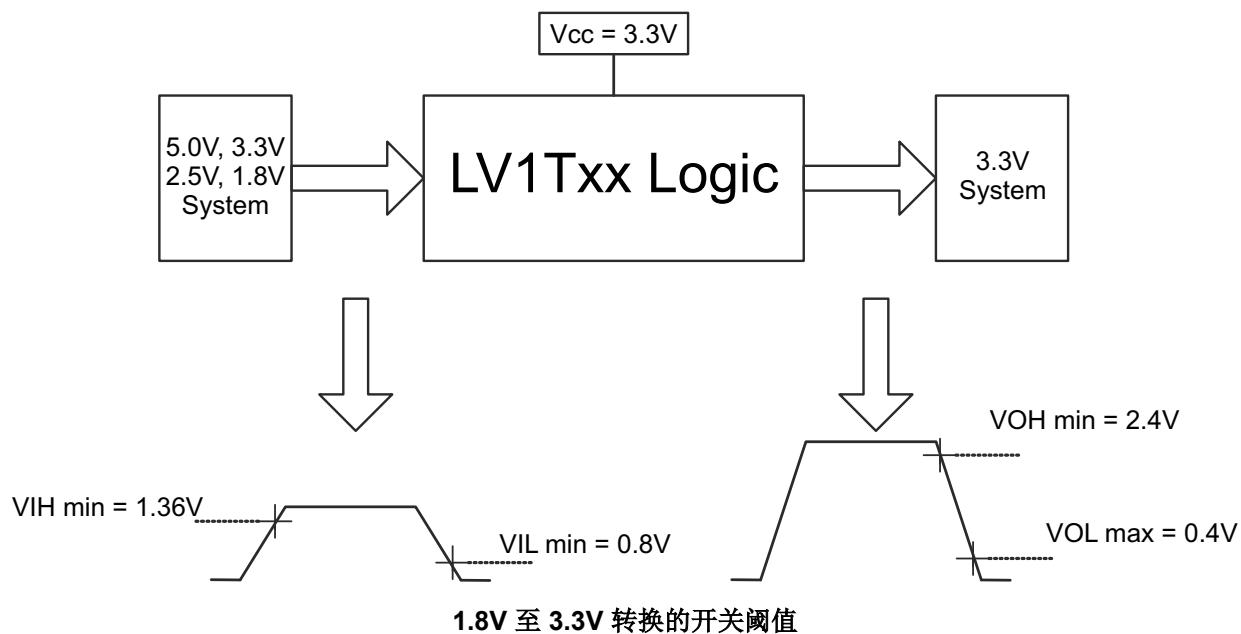


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4 Related Products

DEVICE	PACKAGE	DESCRIPTION
SN74LV1T00	DCK, DBV	2-Input Positive-NAND Gate
SN74LV1T02	DCK, DBV	2-Input Positive-NOR Gate
SN74LV1T04	DCK, DBV	Inverter Gate
SN74LV1T08	DCK, DBV	2-Input Positive-AND Gate
SN74LV1T17	DCK, DBV	Single Schmitt-Trigger Buffer Gate
SN74LV1T14	DCK, DBV	Single Schmitt-Trigger Inverter Gate
SN74LV1T32	DCK, DBV	2-Input Positive-OR Gate
SN74LV1T34	DCK, DBV	Single Buffer Gate
SN74LV1T86	DCK, DBV	Single 2-Input Exclusive-Or Gate
SN74LV1T125	DCK, DBV	Single Buffer Gate with 3-state Output
SN74LV1T126	DCK, DBV	Single Buffer Gate with 3-state Output
SN74LV4T125	RGY, PW	Quadruple Bus Buffer Gate With 3-State Outputs

5 Pin Configuration and Functions

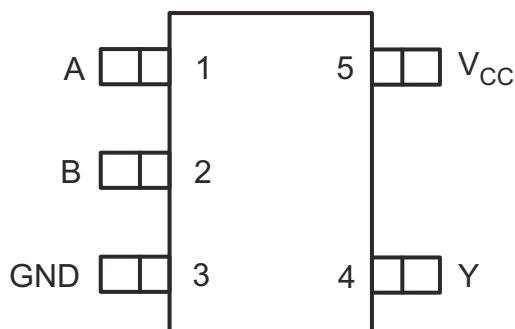


图 5-1. DCK or DBV Package, 5-Pin SC70 or SOT-23 (Top View)

表 5-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.		
A	1	I	Input A
B	2	I	Input B
GND	3	G	Ground
Y	4	O	Output Y
V _{CC}	5	P	Positive supply

(1) I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V_{CC}	Supply voltage range	- 0.5	7.0	V
V_I	Input voltage range ⁽²⁾	- 0.5	7.0	V
V_O	Voltage range applied to any output in the high-impedance or power-off state ⁽²⁾	- 0.5	4.6	V
	Voltage range applied to any output in the high or low state ⁽²⁾	- 0.5	$V_{CC} + 0.5$	V
I_{IK}	Input clamp current	$V_I < 0$		- 20 mA
I_{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20 mA
I_O	Continuous output current			±25 mA
	Continuous current through V_{CC} or GND			±50 mA
T_J	Junction temperature			150 °C
T_{stg}	Storage temperature	- 65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.2 ESD Ratings

		VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000
		Machine Model (MM), per JEDEC specification	±200
		Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1000

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.6	5.5	V
V_I	Input voltage	0	5.5	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.8$ V	- 3	mA
		$V_{CC} = 2.5$ V	- 5	
		$V_{CC} = 3.3$ V	- 7	
		$V_{CC} = 5.0$ V	- 8	
I_{OL}	Low-level output current	$V_{CC} = 1.8$ V	3	mA
		$V_{CC} = 2.5$ V	5	
		$V_{CC} = 3.3$ V	7	
		$V_{CC} = 5.0$ V	8	
$\Delta t / \Delta v$	Input transition rise or fall rate	$V_{CC} = 1.8$ V	20	ns/V
		$V_{CC} = 3.3$ V or 2.5 V	20	
		$V_{CC} = 5.0$ V	20	
T_A	Operating free-air temperature	- 40	125	°C

- (1) All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number [SCBA004](#).

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		DBV	DCK	UNIT
		5 PINS	5 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	278	289.2	°C/W

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	$T_A = 25^\circ\text{C}$			$T_A = -40^\circ\text{C to } +125^\circ\text{C}$			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
V_{IH}	High-level input voltage	$V_{CC} = 1.65\text{ V to } 1.8\text{ V}$	0.94			1.0			V
		$V_{CC} = 2.0\text{ V}$	1.02			1.03			
		$V_{CC} = 2.25\text{ V to } 2.5\text{ V}$	1.135			1.18			
		$V_{CC} = 2.75\text{ V}$	1.21			1.23			
		$V_{CC} = 3\text{ V to } 3.3\text{ V}$	1.35			1.37			
		$V_{CC} = 3.6\text{ V}$	1.47			1.48			
		$V_{CC} = 4.5\text{ V to } 5.0\text{ V}$	2.02			2.03			
		$V_{CC} = 5.5\text{ V}$	2.1			2.11			
V_{IL}	Low-level input voltage	$V_{CC} = 1.65\text{ V to } 2.0\text{ V}$			0.58			0.55	V
		$V_{CC} = 2.25\text{ V to } 2.75\text{ V}$			0.75			0.71	
		$V_{CC} = 3\text{ V to } 3.6\text{ V}$			0.8			0.65	
		$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$			0.8			0.8	
V_{OH}	High-level output voltage	$I_{OH} = -20\text{ }\mu\text{A}$	$1.65\text{ V to } 5.5\text{ V}$	$V_{CC} - 0.1$		$V_{CC} - 0.1$			V
		$I_{OH} = -2.0\text{ mA}$	1.65 V	1.28		1.21			
			1.8 V	1.5		1.45			
		$I_{OH} = -3\text{ mA}$	2.3 V	2		1.93			
		$I_{OH} = -3\text{ mA}$	2.5 V	2.25		2.15			
		$I_{OH} = -3.0\text{ mA}$	3.0 V	2.78		2.7			
		$I_{OH} = -5.5\text{ mA}$		2.6		2.49			
		$I_{OH} = -5.5\text{ mA}$	3.3 V	2.9		2.8			
		$I_{OH} = -4\text{ mA}$	4.5 V	4.2		4.1			
		$I_{OH} = -8\text{ mA}$		4.1		3.95			
		$I_{OH} = -8\text{ mA}$	5.0 V	4.6		4.5			
V_{OL}	Low-level output voltage	$I_{OL} = 20\text{ }\mu\text{A}$	$1.65\text{ V to } 5.5\text{ V}$		0.1			0.1	V
		$I_{OL} = 2\text{ mA}$	1.65 V		0.2			0.25	
		$I_{OL} = 3\text{ mA}$	2.3 V		0.15			0.2	
		$I_{OL} = 3\text{ mA}$	3.0 V		0.1			0.15	
		$I_{OL} = 5.5\text{ mA}$			0.2			0.252	
		$I_{OL} = 4\text{ mA}$	4.5 V		0.15			0.2	
		$I_{OL} = 8\text{ mA}$			0.3			0.35	
I_I	Input leakage current	A input; $V_I = 0\text{ V or } V_{CC}$	0 V, 1.8 V, 2.5 V, 3.3 V, 5.5 V		0.1			± 1	$\mu\text{ A}$
I_{CC}	Static supply current	$V_I = 0\text{ V or } V_{CC}$, $I_O = 0$; open on loading	5.0 V		1			10	$\mu\text{ A}$
			3.3 V		1			10	
			2.5 V		1			10	
			1.8 V		1			10	

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C			T _A = -40°C to +125°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
ΔI_{CC} Additional static supply current	One input at 0.3 V or 3.4 V, Other inputs at 0 or V _{CC} , I _O = 0	5.5 V			1.35			1.5	mA
	One input at 0.3 V or 1.1 V, Other inputs at 0 or V _{CC} , I _O = 0	1.8 V			10			10	μA
C _i Input capacitance	V _I = V _{CC} or GND	3.3 V		2	10		2	10	pF
C _o Output capacitance	V _O = V _{CC} or GND	3.3 V		2.5			2.5		pF

6.6 Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see [Parameter Measurement Information](#))

PARAMETER	FROM (INPUT)	TO (OUTPUT)	FREQUENCY (TYP)	V _{CC}	C _L	T _A = 25°C			T _A = -65°C to 125°C			UNIT
						MIN	TYP	MAX	MIN	TYP	MAX	
t _{pd}	Any In	Y	DC to 50 MHz	5.0 V	15 pF		4	5		4	5	ns
					30 pF		5.5	7.0		5.5	7.0	
				3.3 V	15 pF		4.8	5		5	5.5	ns
					30 pF		5	5.5		5.5	6.5	
			DC to 25 MHz	2.5 V	15 pF		6	6.5		7	7.5	ns
					30 pF		6.5	7.5		7.5	8.5	
			DC to 15 MHz	1.8 V	15 pF		10.5	11		11	12	ns
					30 pF		12	13		12	14	

6.7 Operating Characteristics

T_A = 25°C

PARAMETER	TEST CONDITIONS	V _{CC}	TYP	UNIT
C _{pd} Power dissipation capacitance	f = 1 MHz and 10 MHz	1.8 V ± 0.15 V	14	pF
		2.5 V ± 0.2 V	14	
		3.3 V ± 0.3 V	14	
		5.5 V ± 0.5 V	14	

6.8 Typical Characteristics

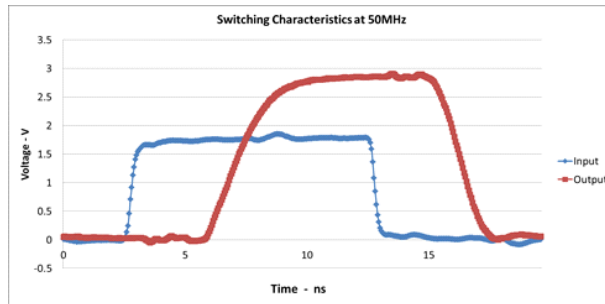


图 6-1. Excellent Signal Integrity
(1.8 V to 3.3 V at 3.3-V V_{CC})

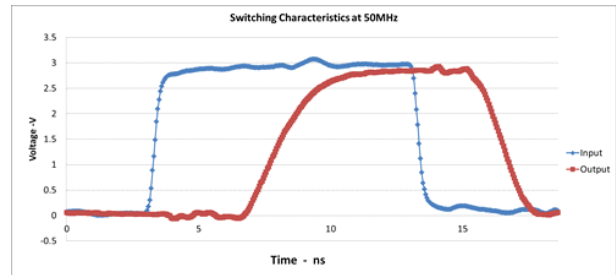


图 6-2. Excellent Signal Integrity
(3.3 V to 3.3 V at 3.3-V V_{CC})

6.8 Typical Characteristics (continued)

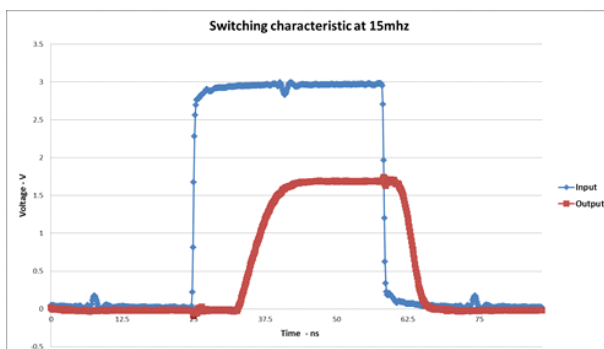
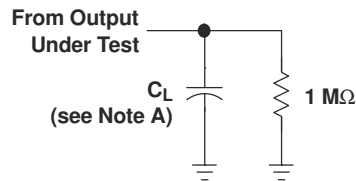


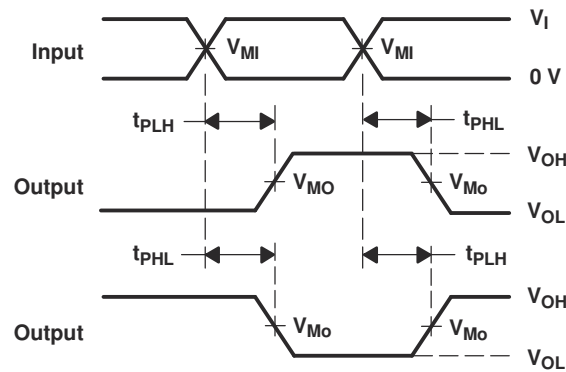
图 6-3. Excellent Signal Integrity
(3.3 V to 1.8 V at 1.8-V V_{CC})

7 Parameter Measurement Information



LOAD CIRCUIT

	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}$	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$
C_L	5, 10, 15, 30 pF	5, 10, 15, 30 pF
V_{MI}	$V_I/2$	$V_I/2$
V_{MO}	$V_{CC}/2$	$V_{CC}/2$



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS

- NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, slew rate $\geq 1\text{ V/ns}$.
C. The outputs are measured one at a time, with one transition per measurement.
D. t_{PLH} and t_{PHL} are the same as t_{pd} .

图 7-1. Load Circuit and Voltage Waveforms

8 Detailed Description

8.1 Overview

The SN74LV1T02 device is a low-voltage CMOS gate logic that operates at a wider voltage range for industrial, portable, telecom, and automotive applications. The output level is referenced to the supply voltage and is able to support 1.8-V, 2.5-V, 3.3-V, and 5-V CMOS levels. The input is designed with a lower threshold circuit to match 1.8 V input logic at $V_{CC} = 3.3$ V and can be used in 1.8 V to 3.3 V level-up translation. In addition, the 5 V tolerant input pins enable down translation (that is, 3.3 V to 2.5 V output at $V_{CC} = 2.5$ V). The wide V_{CC} range of 1.8 V to 5.5 V allows generation of desired output levels to connect to controllers or processors. The SN74LV1T02 device is designed with current-drive capability of 8 mA to reduce line reflections, overshoot, and undershoot caused by high-drive outputs.

8.2 Functional Block Diagram

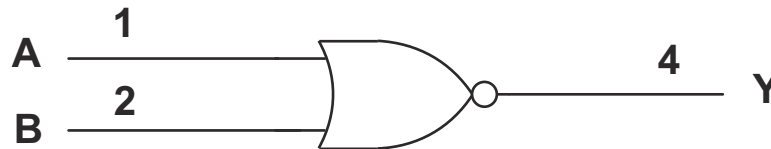


图 8-1. Logic Diagram

8.3 Feature Description

8.3.1 Clamp Diode Structure

The outputs to this device have both positive and negative clamping diodes, and the inputs to this device have negative clamping diodes only as depicted in 图 8-2.

小心

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

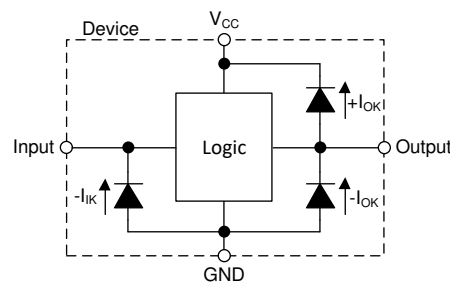


图 8-2. Electrical Placement of Clamping Diodes for Each Input and Output

8.3.2 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

8.3.3 LVxT Enhanced Input Voltage

The SN74LV1T02 belongs to TI's LVxT family of Logic devices with integrated voltage level translation. This family of devices was designed with reduced input voltage thresholds to support up-translation, and inputs tolerant of signals with up to 5.5 V levels to support down-translation. The output voltage will always be referenced to the supply voltage (V_{CC}), as described in the *Electrical Characteristics* table. To ensure proper functionality, input signals must remain at or below the specified $V_{IH(MIN)}$ level for a HIGH input state, and at or below the specified $V_{IL(MAX)}$ for a LOW input state. 图 8-3 shows the typical V_{IH} and V_{IL} levels for the LVxT family of devices, as well as the voltage levels for standard CMOS devices for comparison.

The inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law ($R = V \div I$).

The inputs require that input signals transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and could cause oscillations. More details can be found in the *Implications of Slow or Floating CMOS Inputs* application report.

Do not leave inputs floating at any time during operation. Unused inputs must be terminated at V_{CC} or GND. If a system will not be actively driving an input at all times, a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; however, a 10-k Ω resistor is recommended and will typically meet all requirements.

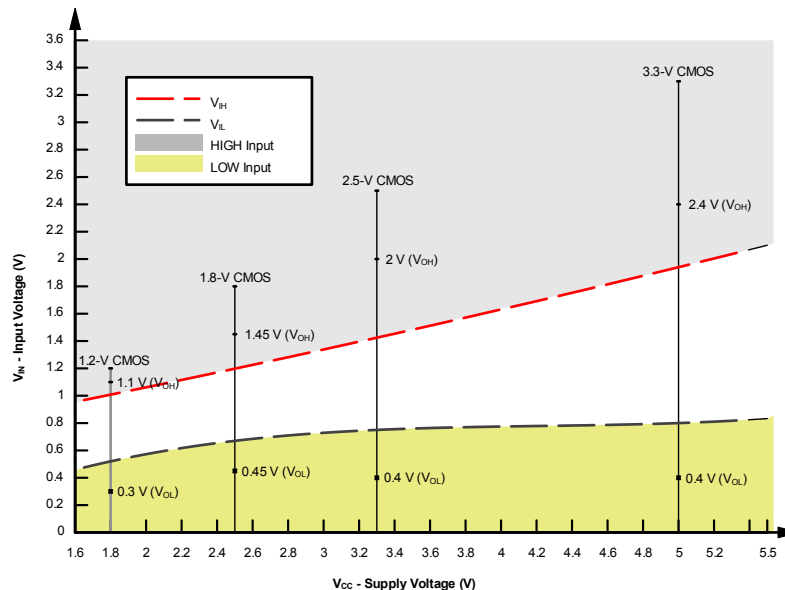


图 8-3. LVxT Input Voltage Levels

8.3.3.1 Down Translation

Signals can be translated down using the SN74LV1T02. The voltage applied at the V_{CC} will determine the output voltage and the input thresholds as described in the *Recommended Operating Conditions* and *Electrical Characteristics* tables.

When connected to a high-impedance input, the output voltage will be approximately V_{CC} in the HIGH state, and 0 V in the LOW state. Ensure that the input signals in the HIGH state are between $V_{IH(MIN)}$ and 5.5 V, and input signals in the LOW state are lower than $V_{IL(MAX)}$ as shown in 图 8-3.

For example, standard CMOS inputs for devices operating at 5.0 V, 3.3 V or 2.5 V can be down-translated to match 1.8 V CMOS signals when operating from 1.8-V V_{CC} . See 图 8-4.

Down Translation Combinations:

- 1.8-V V_{CC} - Inputs from 2.5 V, 3.3 V, and 5.0 V
- 2.5-V V_{CC} - Inputs from 3.3 V and 5.0 V
- 3.3-V V_{CC} - Inputs from 5.0 V

8.3.3.2 Up Translation

Input signals can be up translated using the SN74LV1T02. The voltage applied at V_{CC} will determine the output voltage and the input thresholds as described in the *Recommended Operating Conditions* and *Electrical Characteristics* tables. When connected to a high-impedance input, the output voltage will be approximately V_{CC} in the HIGH state, and 0 V in the LOW state.

The inputs have reduced thresholds that allow for input high-state levels which are much lower than standard values. For example, standard CMOS inputs for a device operating at a 5-V supply will have a $V_{IH(MIN)}$ of 3.5 V. For the SN74LV1T02, $V_{IH(MIN)}$ with a 5-V supply is only 2 V, which would allow for up-translation from a typical 2.5-V to 5-V signals.

Ensure that the input signals in the HIGH state are above $V_{IH(MIN)}$ and input signals in the LOW state are lower than $V_{IL(MAX)}$ as shown in 图 8-4.

Up Translation Combinations:

- 1.8-V V_{CC} - Inputs from 1.2 V
- 2.5-V V_{CC} - Inputs from 1.8 V
- 3.3-V V_{CC} - Inputs from 1.8 V and 2.5 V
- 5.0-V V_{CC} - Inputs from 2.5 V and 3.3 V

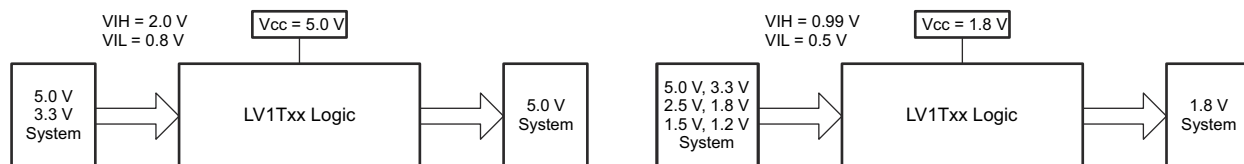


图 8-4. LVxT Up and Down Translation Example

8.4 Device Functional Modes

Function Table

INPUT ⁽¹⁾ (LOWER LEVEL INPUT)		OUTPUT ⁽²⁾ (V_{CC} CMOS)
A	B	Y
H	X	L
X	H	L
L	L	H
SUPPLY $V_{CC} = 3.3\text{ V}$		
A	B	Y
$V_{IH(min)} = 1.35\text{ V}$ $V_{IL(max)} = 0.08\text{ V}$		$V_{OH(min)} = 2.9\text{ V}$ $V_{OL(max)} = 0.2\text{ V}$

- (1) H = High Voltage Level, L = Low Voltage Level, X = Do not Care, Z = High Impedance
 (2) H = Driving High, L = Driving Low, Z = High Impedance State

9 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A $0.1\text{-}\mu\text{F}$ capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The $0.1\text{-}\mu\text{F}$ and $1\text{-}\mu\text{F}$ capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in the following layout example.

9.2 Layout

9.2.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

9.2.2 Layout Example

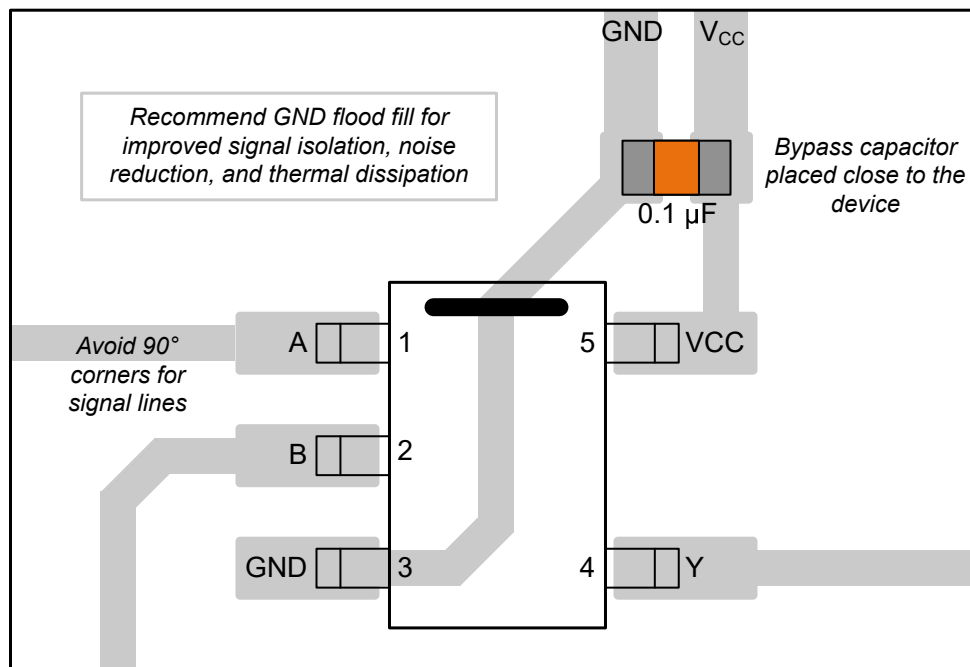


图 9-1. Example Layout for the SN74LV1T02

10 Device and Documentation Support

10.1 接收文档更新通知

要接收文档更新通知，请导航至 [ti.com](https://www.ti.com) 上的器件产品文件夹。点击 [通知](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

10.2 支持资源

[TI E2E™ 中文支持论坛](#) 是工程师的重要参考资料，可直接从专家处获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题，获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [使用条款](#)。

10.3 Trademarks

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10.4 静电放电警告



静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序，可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

10.5 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

11 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision C (October 2023) to Revision D (August 2024)	Page
• Updated R _{θJA} values: DBV = 206 to 278, all values in °C/W	7
• Added image in <i>Layout Example</i> section.....	14

Changes from Revision B (June 2022) to Revision C (October 2023)	Page
• Updated R _{θJA} values: DCK = 252 to 289.2, all values in °C/W	7
• Added Typical Characteristics.....	8

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
SN74LV1T02DBVR	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU SN NIPDAU	Level-1-260C-UNLIM	-40 to 125	(3JRH, NEB3, NEBJ, NEBS)
SN74LV1T02DBVR.A	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(3JRH, NEB3, NEBJ, NEBS)
SN74LV1T02DBVRG4	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	NEB3
SN74LV1T02DBVRG4.A	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	NEB3
SN74LV1T02DCKR	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(1QW, WB3, WBJ, WB S)
SN74LV1T02DCKR.A	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(1QW, WB3, WBJ, WB S)
SN74LV1T02DCKRG4	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-	WB3
SN74LV1T02DCKRG4.A	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	WB3

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74LV1T02 :

- Automotive : [SN74LV1T02-Q1](#)

NOTE: Qualified Version Definitions:

- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV1T02DBVR	SOT-23	DBV	5	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LV1T02DBVRG4	SOT-23	DBV	5	3000	178.0	9.2	3.3	3.23	1.55	4.0	8.0	Q3
SN74LV1T02DCKR	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
SN74LV1T02DCKRG4	SC70	DCK	5	3000	178.0	9.2	2.4	2.4	1.22	4.0	8.0	Q3

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV1T02DBVR	SOT-23	DBV	5	3000	210.0	185.0	35.0
SN74LV1T02DBVRG4	SOT-23	DBV	5	3000	180.0	180.0	18.0
SN74LV1T02DCKR	SC70	DCK	5	3000	180.0	180.0	18.0
SN74LV1T02DCKRG4	SC70	DCK	5	3000	180.0	180.0	18.0

DCK0005A



PACKAGE OUTLINE

SOT - 1.1 max height

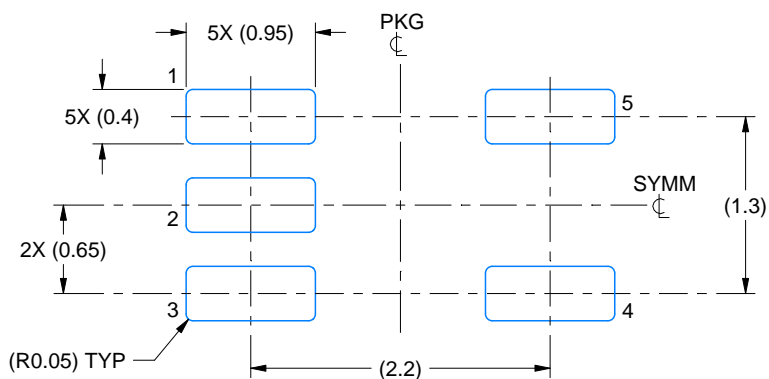
SMALL OUTLINE TRANSISTOR



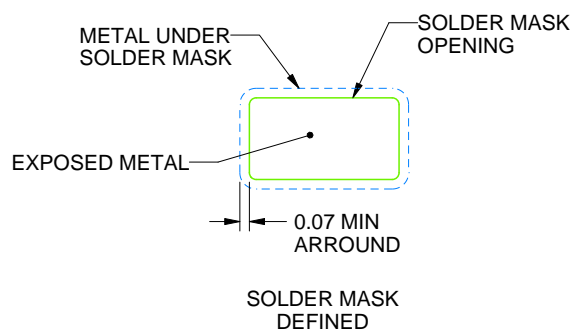
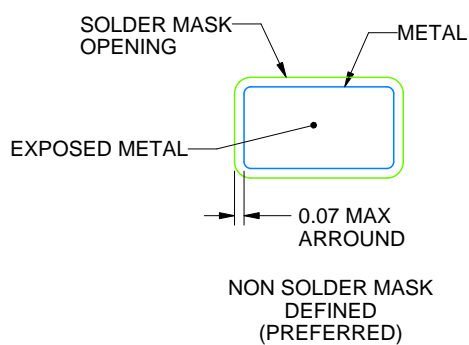
4214834/G 11/2024

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-203.
4. Support pin may differ or may not be present.
5. Lead width does not comply with JEDEC.
6. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25mm per side.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:18X



SOLDER MASK DETAILS

4214834/G 11/2024

NOTES: (continued)

7. Publication IPC-7351 may have alternate designs.

8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 THICK STENCIL
SCALE:18X

4214834/G 11/2024

NOTES: (continued)

9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
10. Board assembly site may have different recommendations for stencil design.

EXAMPLE STENCIL DESIGN

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4214839/K 08/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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